

<b>Beamline</b>	<b>PF BL-19B</b>			
<b>Sample</b>	<b>SiO<sub>2</sub> (powder on carbon tape)</b>			
<b>Edge</b>	<b>Si-K</b>			
<b>Method</b>	<b>Total electron yield</b>			
<b>Date</b>	<b>2020.10.23</b>			
<b>Scan mode</b>	<b>Quick scan mode</b>			
	<b>Energy /eV</b>	<b>Step /eV</b>	<b>Dwell / s</b>	
	<b>1820</b>	<b>1920</b>	<b>0.1</b>	<b>0.5</b>
	<b>Total data points</b>		<b>1000</b>	
	<b>Measure time</b>		<b>8.3 min</b>	

